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| INFORMATION DISCLOSURE CITATION IN AN APPLICATION <i>(Use several sheets if necessary)</i> | Docket Number (Optional) AKM-00301 | Application No. 525802 |
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| Applicant I. Hidaka | Group Art Unit |
| Filing Date March 15, 2000 | |

U.S. PATENT DOCUMENTS

| EXAMINER INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|---------------------|-----------------|------|------|-------|----------|-------------------------------|
| | AA | | | | | |
| | AB | | | | | |
| | AC | | | | | |
| | AD | | | | | |
| | AE | | | | | |
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| | AJ | | | | | |
| | AK | | | | | |

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FOREIGN PATENT DOCUMENTS

| | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | Translation | |
|----|-----------------|----------|---------|-------|----------|-------------|----|
| | | | | | | YES | NO |
| LC | AL 8-274167 | 10-18-96 | Japan | — | — | | |
| | AM | | | | | | |
| | AN | | | | | | |
| | AO | | | | | | |
| | AP | | | | | | |

OTHER DOCUMENTS*(Including author, Title, Date, Pertinent Pages)*

| | | |
|----|----|-----------------------------------------------------------------------------------------------|
| LC | AQ | "Glossary of Semiconductor and IC terms" (edited by Takahiko Iida et al., Ohmsha, Ltd., 1980) |
| LC | AR | "Comprehensive Glossary of ULSI terms" (issued by Hirotaka Motoyama, Science Forum, Ltd., |
| | AS | 1988) |
| | AT | |
| | AU | |
| | AV | |
| | AW | |
| | AX | |
| | AY | |

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| EXAMINER  | DATE CONSIDERED 6-16-00 |
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

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